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(71) Applicant: **MICRON TECHNOLOGY, INC.** [US/US];
8000 South Federal Way, Boise, ID 83716-9632 (US).

(72) Inventor: **JEDDELOH, Joseph, M.**; 4302 Reiland Lane,
Shoreview, MN 55126 (US).

(74) Agents: **BULCHIS, Edward, W.** et al.; Dorsey & Whit-
ney LLP, 1420 Fifth Avenue, Suite 3400, Seattle, WA
98101 (US).

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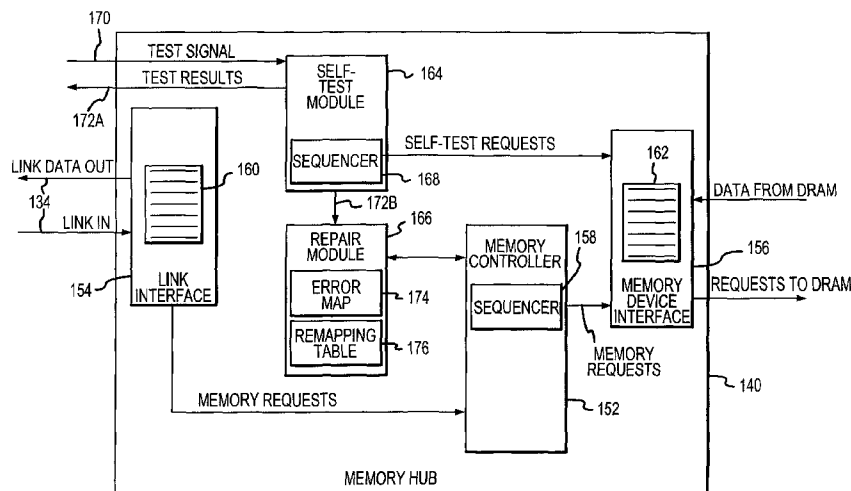
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(54) Title: SYSTEM AND METHOD FOR SELF-TESTING AND REPAIR OF MEMORY MODULES



(57) Abstract: A computer system and a method used to test and repair defective memory portions of memory devices located on a memory module. The computer system includes a memory hub controller coupled to a plurality of memory modules each of which includes a memory hub and a plurality of memory devices. The memory hub comprises a self-test module that determines the locations of defective memory locations of the memory devices. A repair module also included in the memory hub uses the locations of defective memory portions to create a remapping table. The remapping table redirects accesses to the defective locations of the memory devices to non-defective memory locations. Each time the memory hub receives a memory request from a memory access device, the memory hub checks the memory location to which the access is directed, and, if necessary, redirects the memory access to a non-defective location.

WO 2004/017162 A3